

<p style="text-align: center;">LIST OF PRIOR ART CITED BY APPLICANT (PTO-1449)</p> <p style="text-align: right;">JAN 21 2004 SC111 PATENT & TRADEMARK OFFICE</p>				ATTY. DOCKET NO. JHU-0003	APPLN. SERIAL NO. Serial No.:	
				APPLICANT(S) Jonah ERLEBACHER and Yi DING		
				CUSTOMER NO. 34610		
				FILING DATE August 26, 2003	GROUP art unit	
U.S. PATENT DOCUMENTS						
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
/AE/	6329072 B1	12/11/01	Honma et al.	428	618	02/19/98
	4916110	04/10/90	Manniso	502	439	11/01/88
	4977038	12/11/90	Sieradzki et al.	428	610	04/14/89
	3486928	12/30/69	Rhoda et al.	117	130	10/21/65
	6060190	05/09/00	Campbell et al.	429	40	12/21/98
	6368877 B1	04/09/02	Zhang et al.	436	527	06/25/97
/AE/	6391477 B1	05/21/02	Koslov et al.	428	670	07/06/00
U.S. PATENT APPLICATION PUBLICATIONS						
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
U.S. PATENT APPLICATIONS						
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation Yes No
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)						
/AE/	J. Erlebacher et al., "Evolution of nanoporosity in dealloying," Nature, Vol. 410, March 22, 2001, pp. 450-453.					
EXAMINER	/Alix Echelmeyer/		DATE CONSIDERED	03/13/2007		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

<p style="text-align: center;">LIST OF PRIOR ART CITED BY APPLICANT (PTO-1449)</p> <p style="text-align: right;">MAR 17 2004</p> <p style="text-align: right;">U.S. PATENT & TRADEMARK OFFICE</p>				ATTY. DOCKET NO. JHU-0003	APPLN. SERIAL NO. 10/647,436	
				APPLICANT(S) Jonah ERLEBACHER and Yi DING		
				CUSTOMER NO. 34610		
				FILING DATE August 26, 2003	GROUP 1773	
				U.S. PATENT DOCUMENTS		
EXAMINER'S INITIALS	*PATENT NO.	*ISSUE DATE	*INVENTOR NAME	CLASS	SUBCLASS	FILING DATE
/AE/	4255247	3/10/81	Oda et al.	204	293	2/21/78
	4713234	12/15/87	Weirich et al.	423	648	7/1/85
	4801379	1/31/89	Ehram et al.	210	498	7/15/87
	4857080	8/15/89	Baker et al.	55	16	12/2/87
	5753014	5/19/98	Van Rijn	96	12	11/14/94
/AE/	5830680	11/3/98	Meyerhoff et al.	435	7.92	8/15/96
U.S. PATENT APPLICATION PUBLICATIONS						
	*PATENT APPLN. PUB. NO.	*PUB. DATE	*APPLICANT	CLASS	SUBCLASS	
/AE/	2002/0020298	2/21/02	Drost et al.	96	11	
/AE/	2002/0028345	3/7/02	Kempf et al.	428	670	
U.S. PATENT APPLICATIONS						
	*APPLN. NO.	*FILING DATE	*INVENTOR	CLASS	SUBCLASS	
FOREIGN PATENT DOCUMENTS						
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation
/AE/	48-44699	06-1978	JAPAN			Yes
	57-109242	07-1982	JAPAN			No
	61-259722	11-1986	JAPAN			
/AE/	64-070135	03-1989	JAPAN			
OTHER ART (Including Author, Title, Date, Pertinent Pages, Publisher, Place of Publication, Etc.)						
EXAMINER	/Alix Echelmeyer/			DATE CONSIDERED 03/13/2007		

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.